

**Search Notes**

Application/Control No.

10/022,622

Examiner

Feben M. Haile

Applicant(s)/Patent under  
Reexamination

KIM, KI-TAEK

Art Unit

2663

**SEARCHED**

Class	Subclass	Date	Examiner
370	389	2/3/2006	FH
370	395.1	2/3/2006	FH
370	395.7	2/3/2006	FH
370	395.71	2/3/2006	FH
370	412	2/3/2006	FH
370	413	2/3/2006	FH
370	395.6	2/3/2006	FH
370	350	9/7/2006	FH
370	392	9/7/2006	FH
370	398	9/7/2006	FH
370	399	9/7/2006	FH
370	345	9/7/2006	FH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
370	395.1	9/7/2006	FH
370	413	9/7/2006	FH
370	350	9/7/2006	FH
H04L 12/56 H04J 3/06		9/7/2006	fh

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search: atm, cell, fifo, SOC, synchronization, buffer, memory, queue, storage, utopia, discard, remove	2/3/2006	FH
Updated Search	6/1/2006	FH
Updated Search	9/7/2006	FH